Electronic Supplementary Material (ESI) for Physical Chemistry Chemical Physics.

Supporting Information

A multi-technique comparison of the electronic properties of pristine and nitrogen-doped polycrystalline SnO_2.

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Fig. S1 (a)

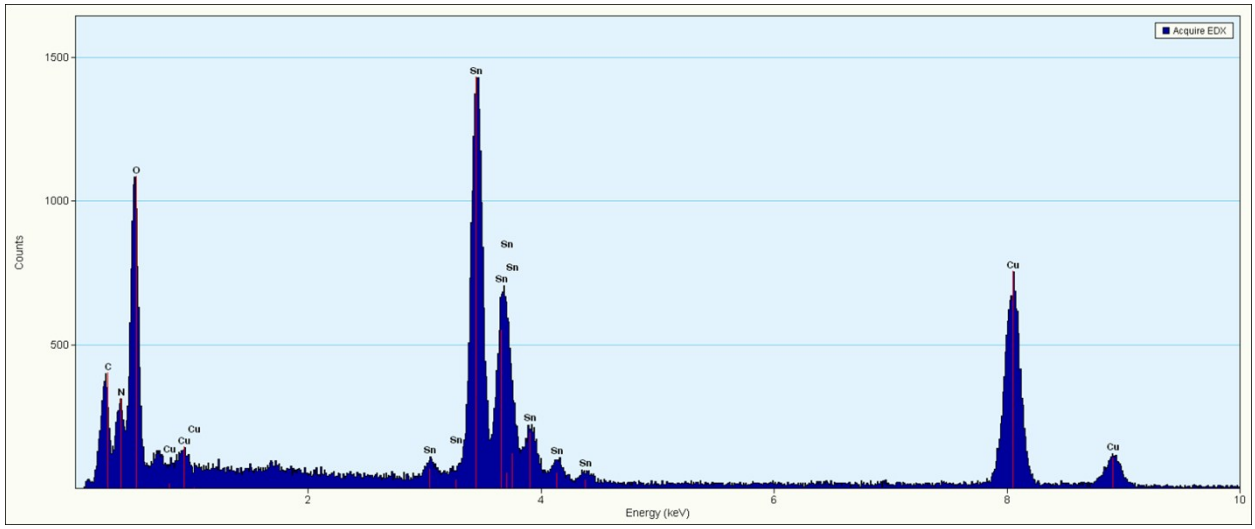
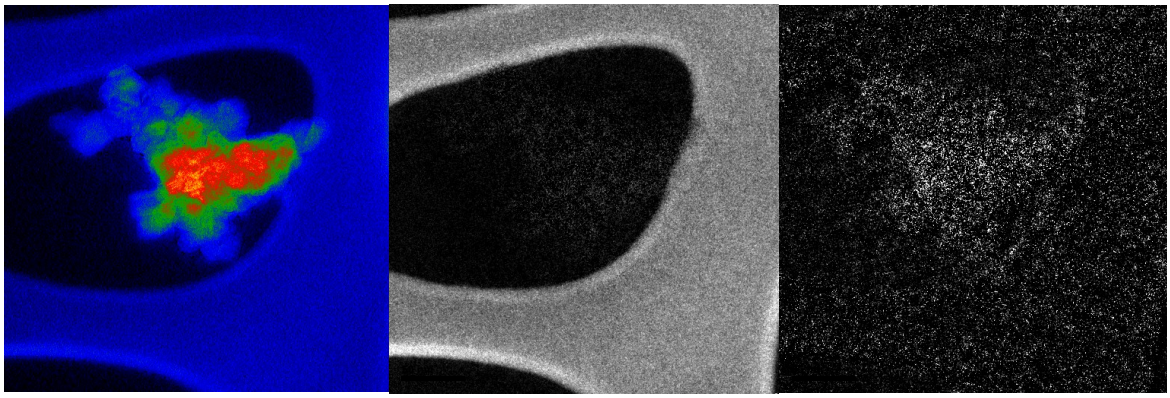


Fig. S1 (b)



Thickness map Carbon map Nitrogen map

Figure S1 : EDX spectrum of N-doped SnO_2 (a) and related EFTEM acquisitions showing thickness, carbon and nitrogen maps